

Evaluating architectural, redundancy, and implementation strategies for radiation hardening of FinFET integrated circuits
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High temperature properties of CdTe crystals, doped by Sb

Fochuk, P.; Grill, R.; Nykonyuk, Y.; **Krustok, Jüri**; Armani, N.; Zakharuk, Z.; **Grossberg, Maarja**; Panchuk, O. IEEE transactions on nuclear science 2007 / 4, p. 763-768